

Pt-Ga catalyst formation studied with *in situ* XAS using Fourier and wavelet transformed analysis.

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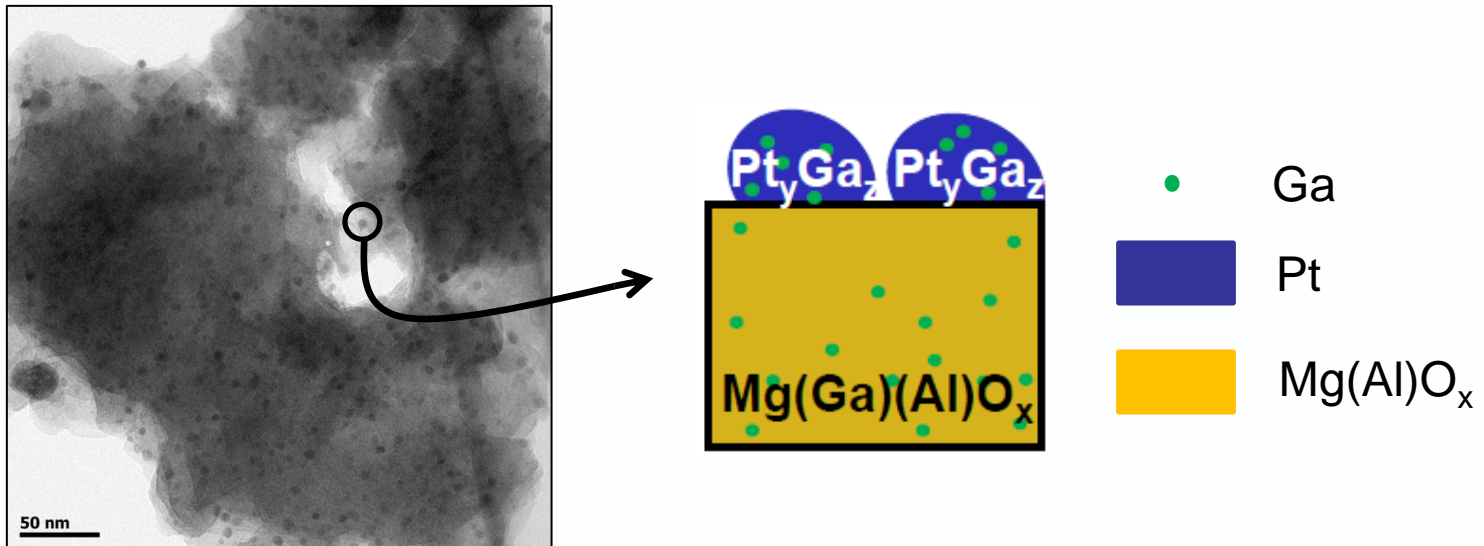
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GdRC(RS)₂, Lille, France, 09/10/2013

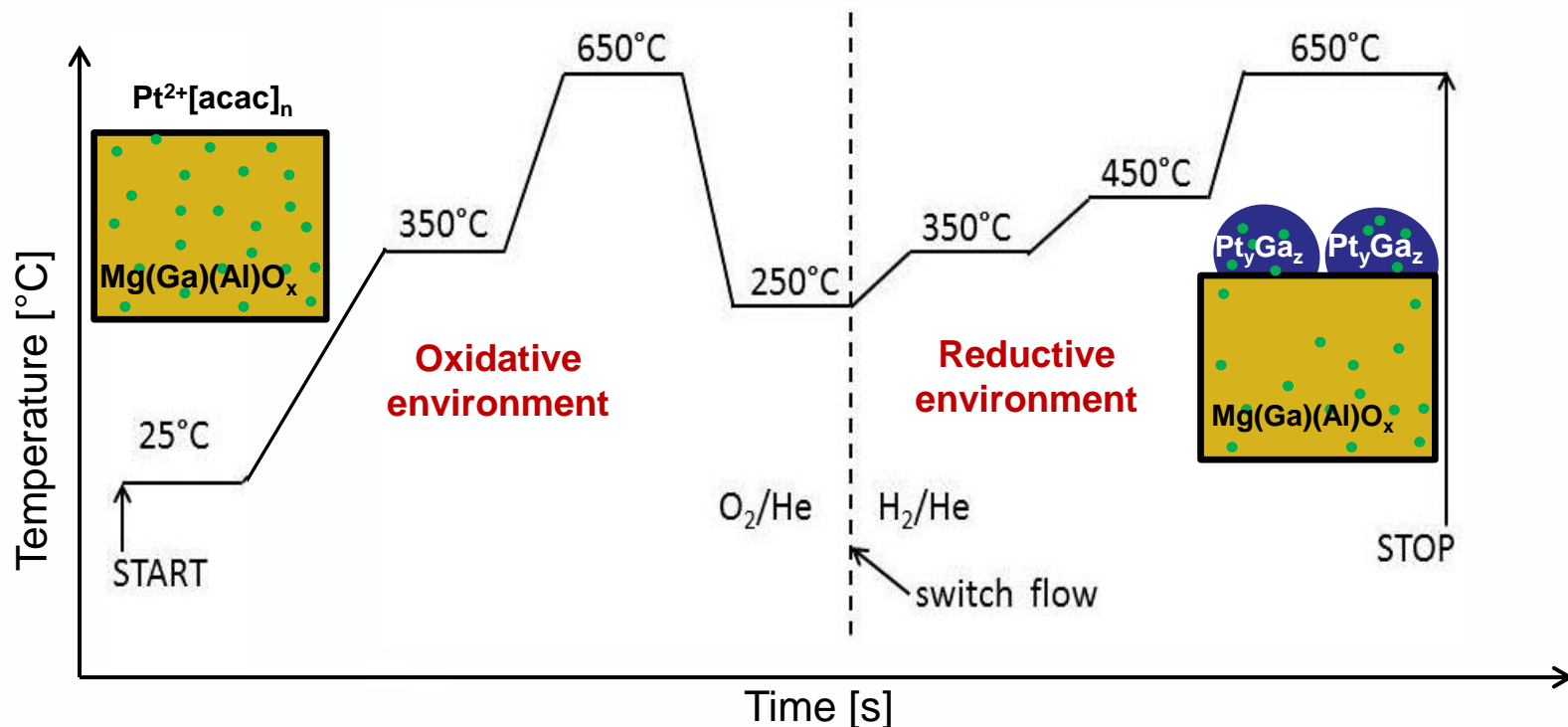
Introduction & Motivation

- Supported Pt-Ga catalysts: alkane dehydrogenation
 - Improved selectivity and stability
 - Major improvements possible
 - Elucidate formation mechanisms: improve performance
- Novel catalyst formation process: intimate Pt-Ga contact
 - Ga in $\text{Mg}(\text{Al})\text{O}_x \rightarrow \text{Mg}(\text{Ga})(\text{Al})\text{O}_x$
 - $\text{Pt}[\text{acac}]_2$ on calcined $\text{Mg}(\text{Ga})(\text{Al})\text{O}_x$
 - Oxidation & reduction \rightarrow Pt-Ga catalyst



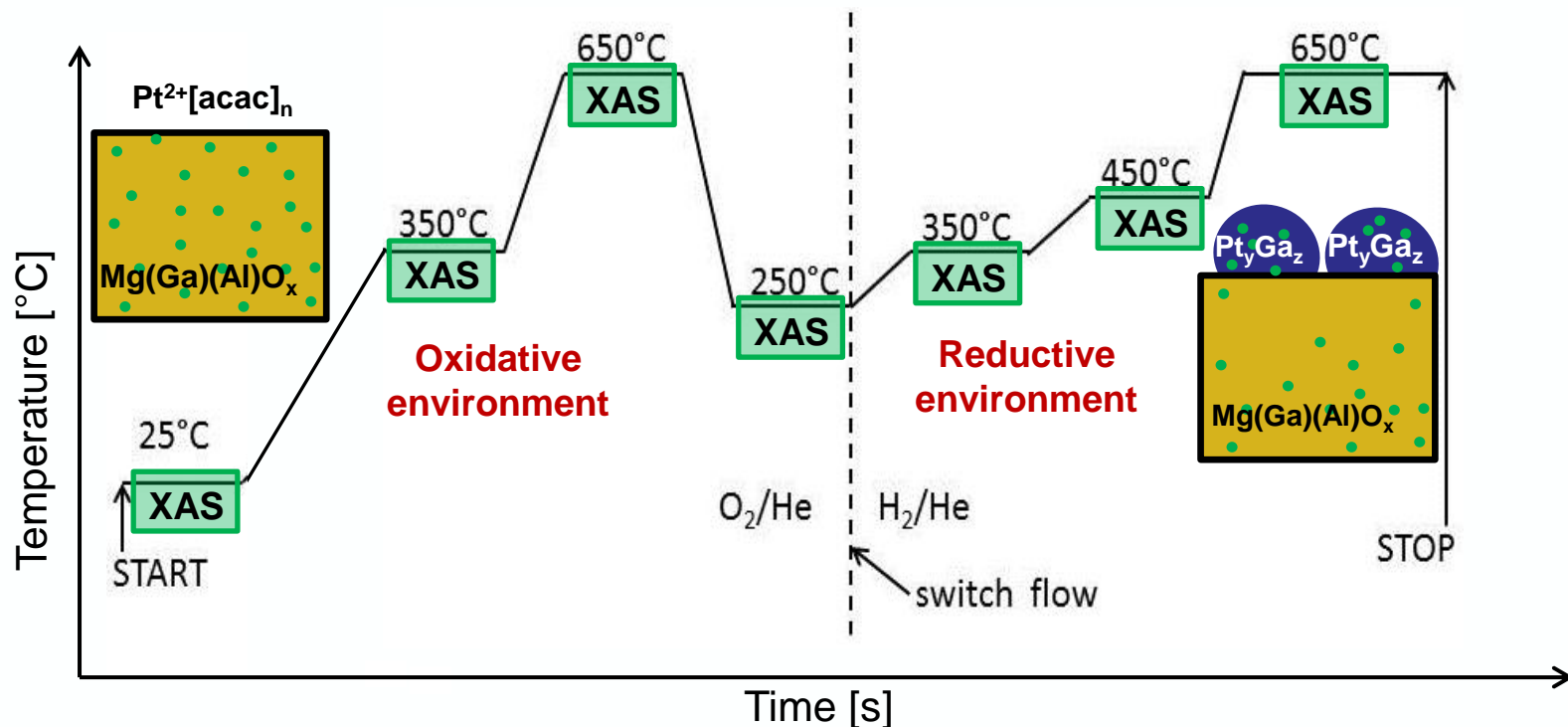
Experiments

- Isothermal *in situ* XAS experiments @ DUBBLE, ESRF
 - Catalyst: Pt[acac]_n/Mg(Ga)(Al)O_x (5 wt% Pt, 3.75 wt% Ga)
 - Capillary quartz tubular reactor (OD = 2 mm)
 - Pt L_{III} edge (11564 eV, transmission)



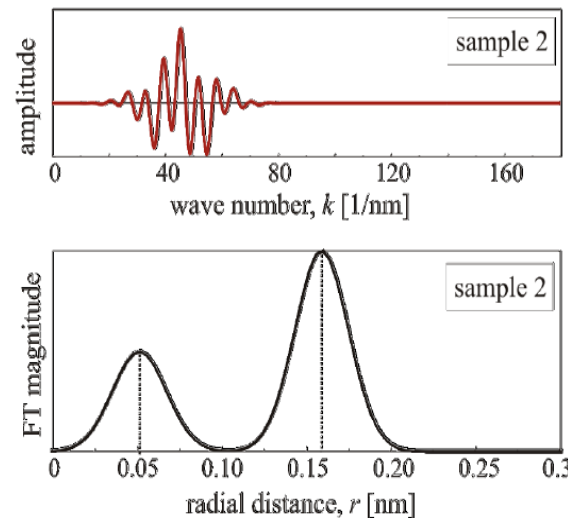
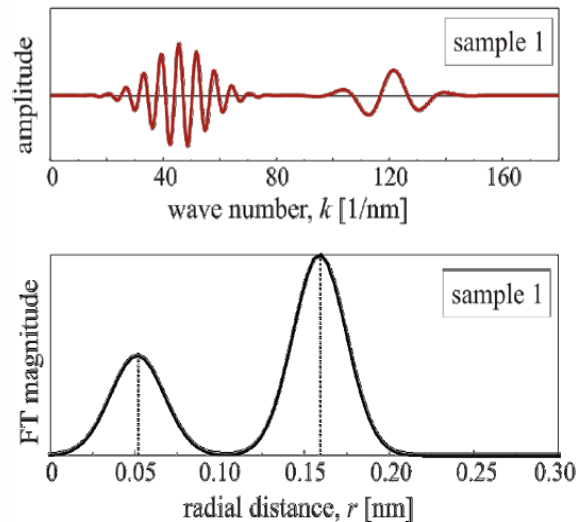
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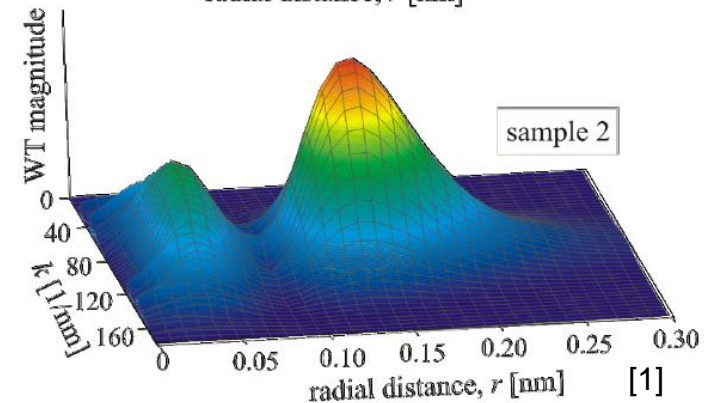
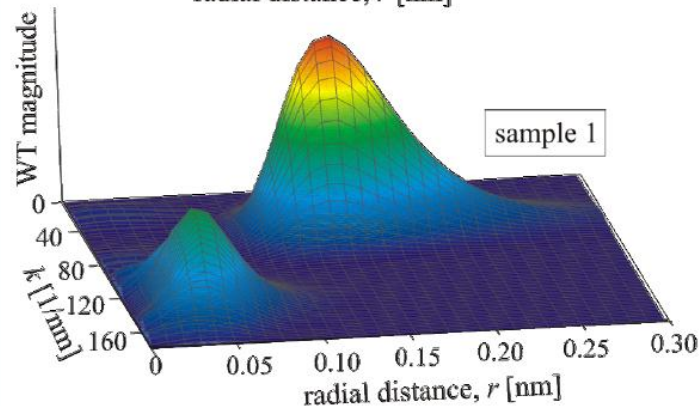
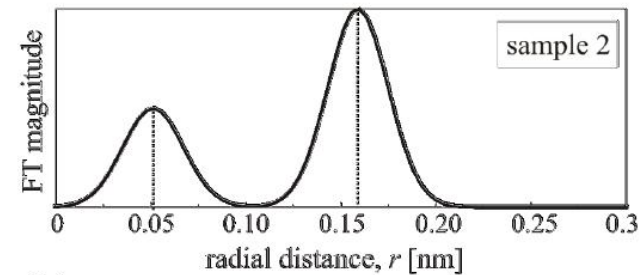
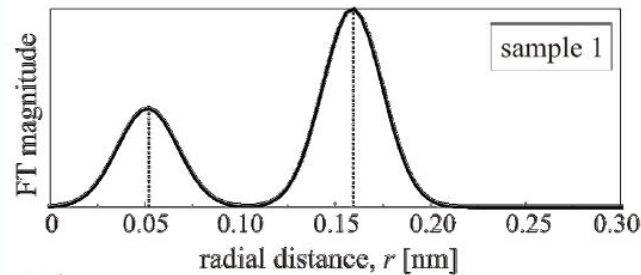
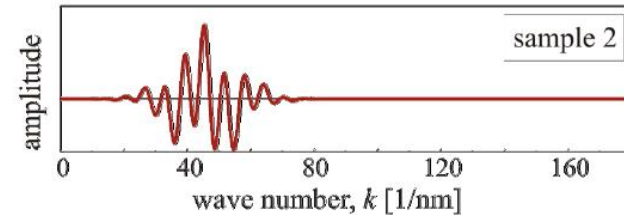
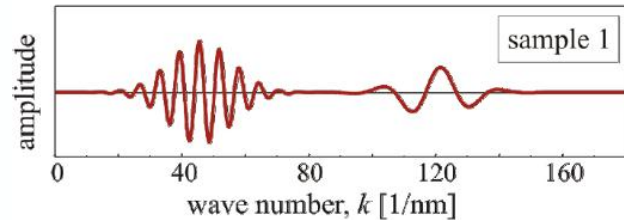
XAS wavelet transforms

- Pt-Ga formation process:
 - variety of Pt neighbors (Pt-C, Pt-O, Pt-Ga, Pt-Pt)
 - Discrimination and localization of different atomic species necessary
- Fourier transformed (FT) signals
 - k-region of backscattering ~ atomic mass: $C < O < Ga < Pt$
 - $2 \neq \text{species}$, $2 \neq \text{locations}$ vs $2 = \text{species}$, $2 \neq \text{locations}$



→ invoke wavelet transformed (WT) XAS analysis

XAS wavelet transforms

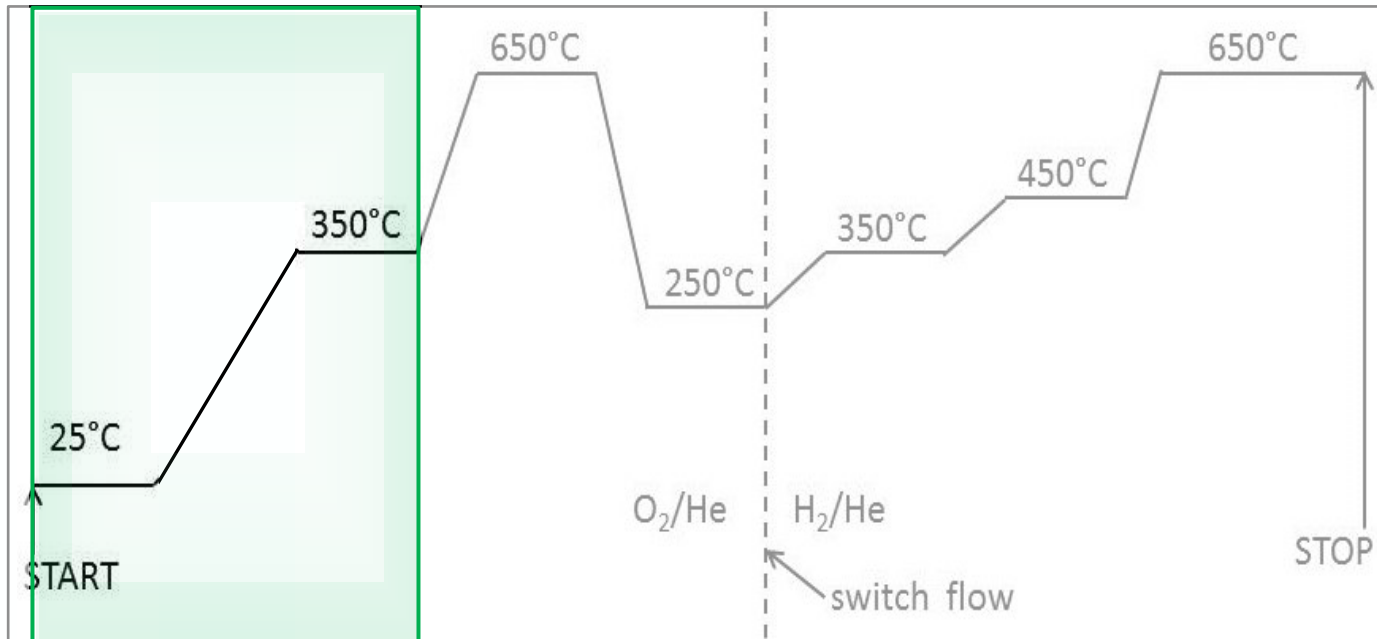


→ simultaneous R and k space resolution^[1,2]: appoint k-space backscattering region to each R-space peak

[1] C. Antoniak, *Beilstein J. Nanotechnol.* **2011**, 2, 237–251

[2] Muñoz M., Argoul P. and Farges F. (2003) *American Mineralogist* vol. 88, pp. 694-700

Results: Region 1



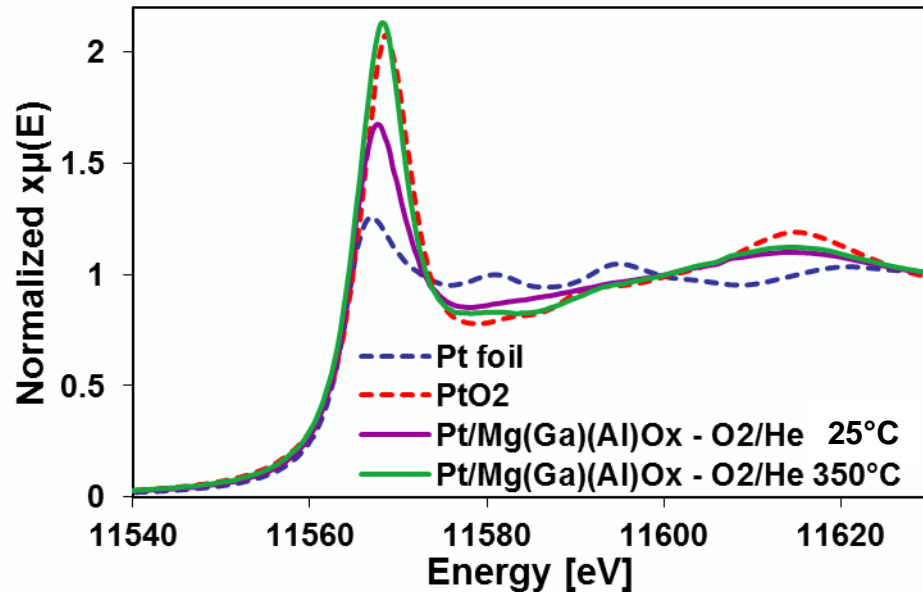
Region 1: 25°C – 350°C in O₂/He

Region 2: 350°C – 650°C – 250°C in O₂/He

Region 3: 250°C – 350°C – 450°C in H₂/He

Region 4: 450°C – 650°C in H₂/He

25°C – 350°C in O₂/He

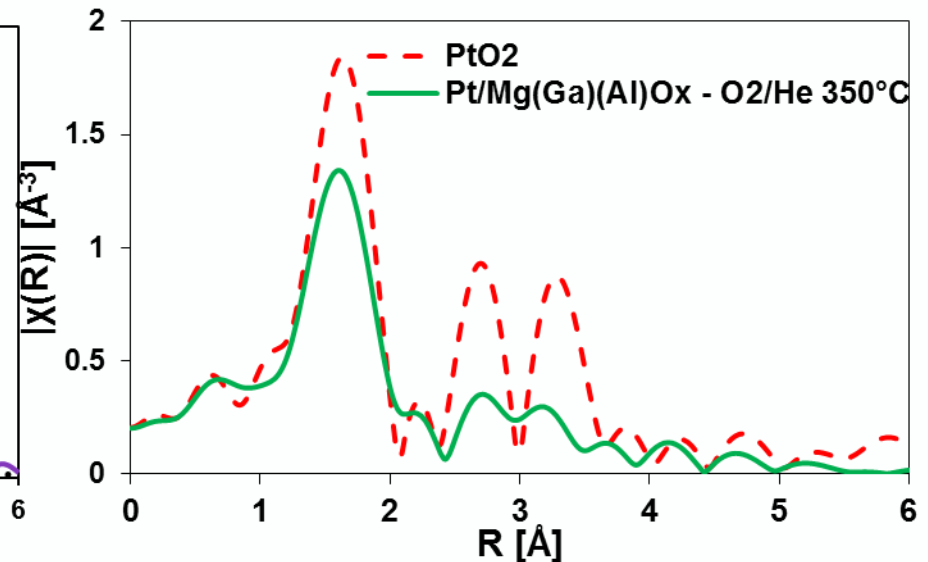
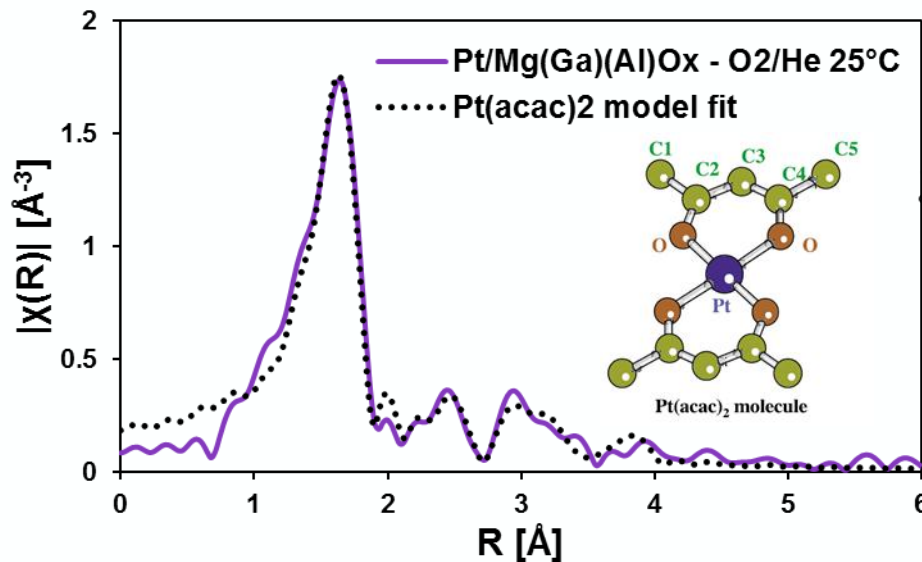


XANES

- WL at 25°C = II+ = Pt²⁺[acac]₂
- Oxidation to 350°C: Pt⁴⁺O₂-like XANES

FT EXAFS

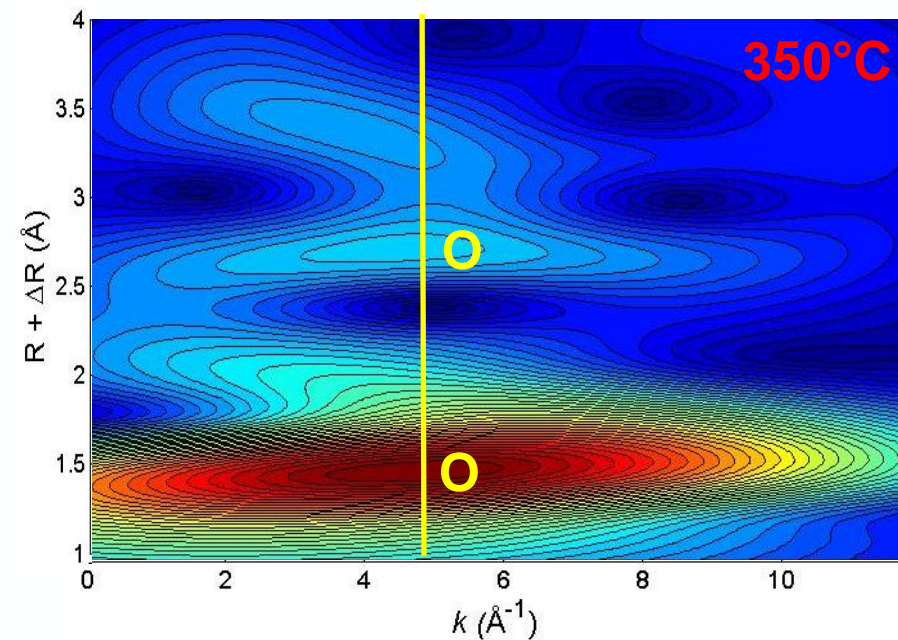
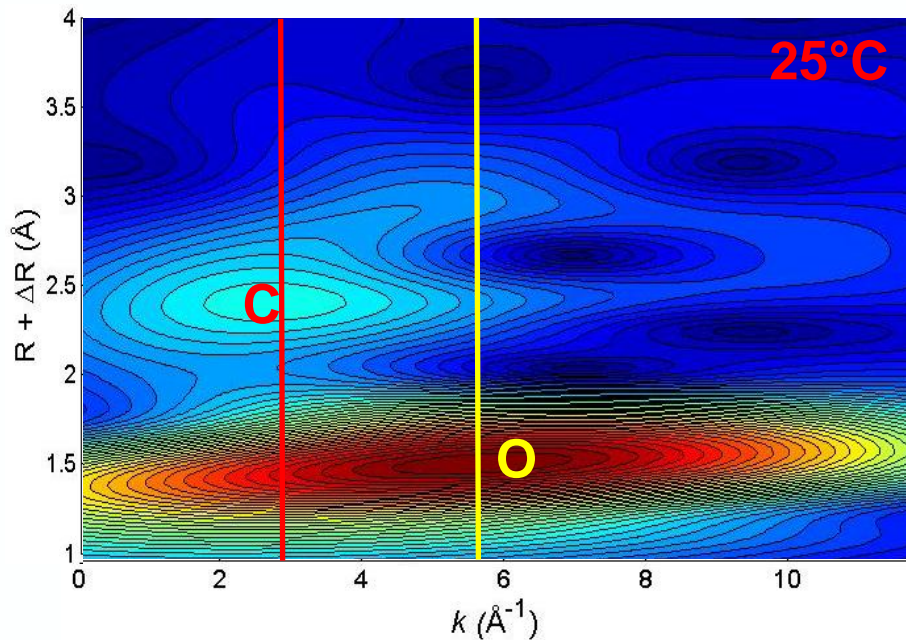
- As prepared catalyst at RT: Pt[acac]₂
- Oxidation to 350°C: dispersed PtO₂



25°C – 350°C in O₂/He

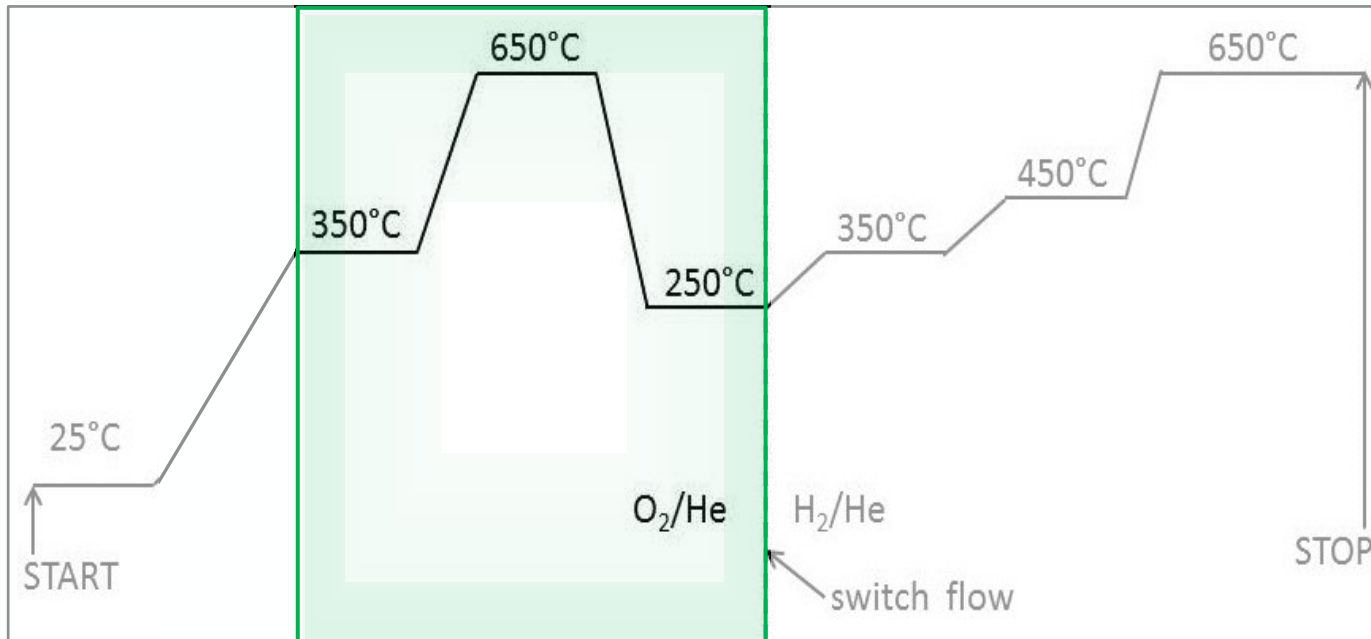
WT EXAFS

- R: radial distribution function around Pt
- k-space resolution for R-space peaks
- C backscatterer (25°C) → O backscatterer (350°C) during oxidation



25°C – 350°C, O₂: Pt[acac]₂ decomposition + dispersed PtO₂ phase formation

Results: Region 2



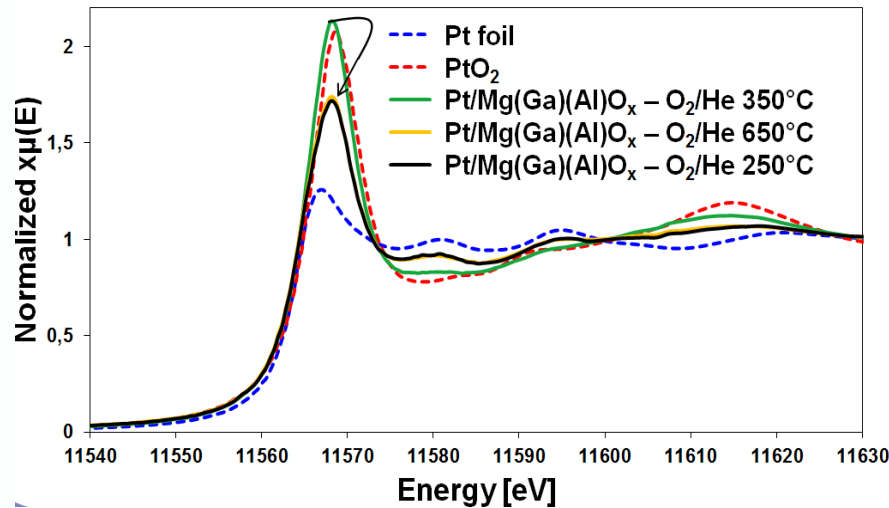
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350°C – 650°C – 250°C in O₂/He

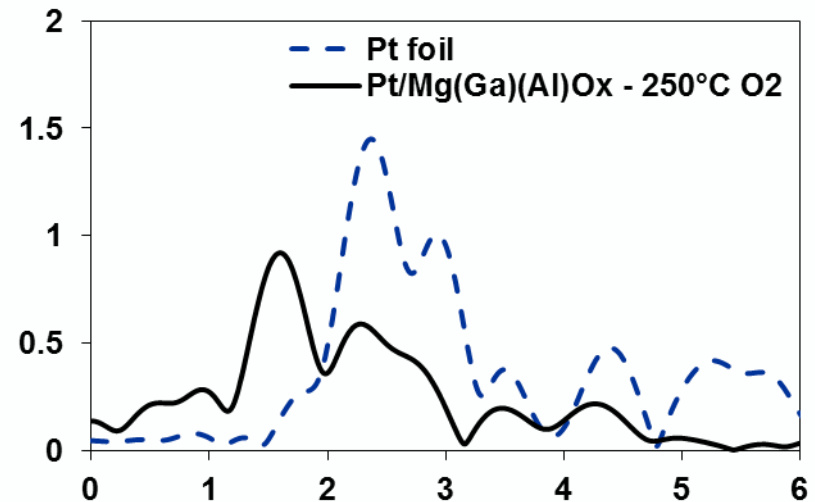
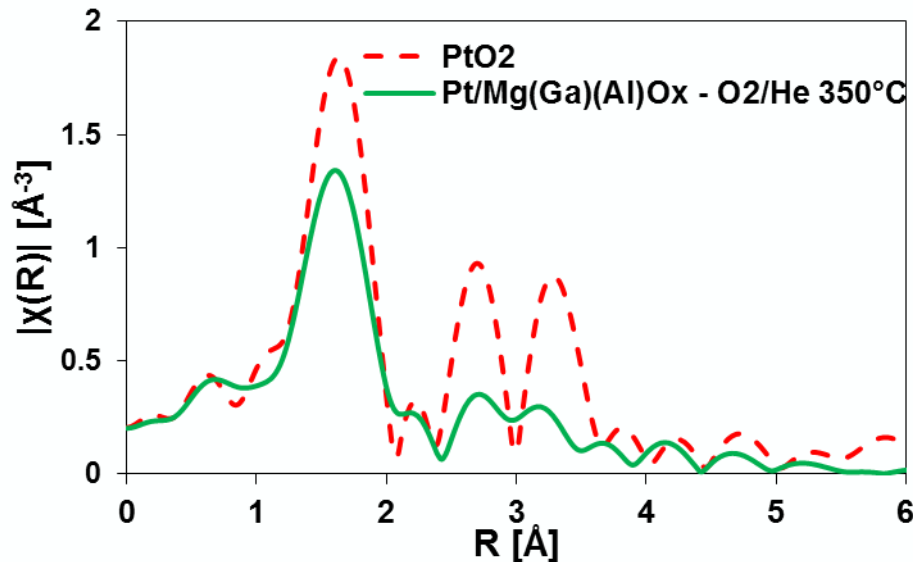


XANES

- Further oxidation up to 650°C: decrease oxidation state
- Cool down to 250°C: no effect

FT EXAFS

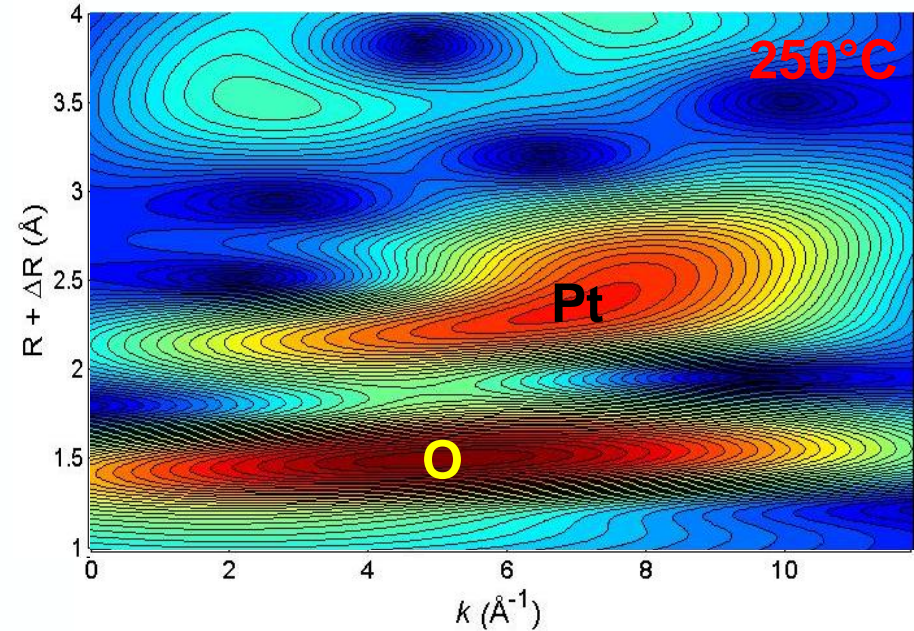
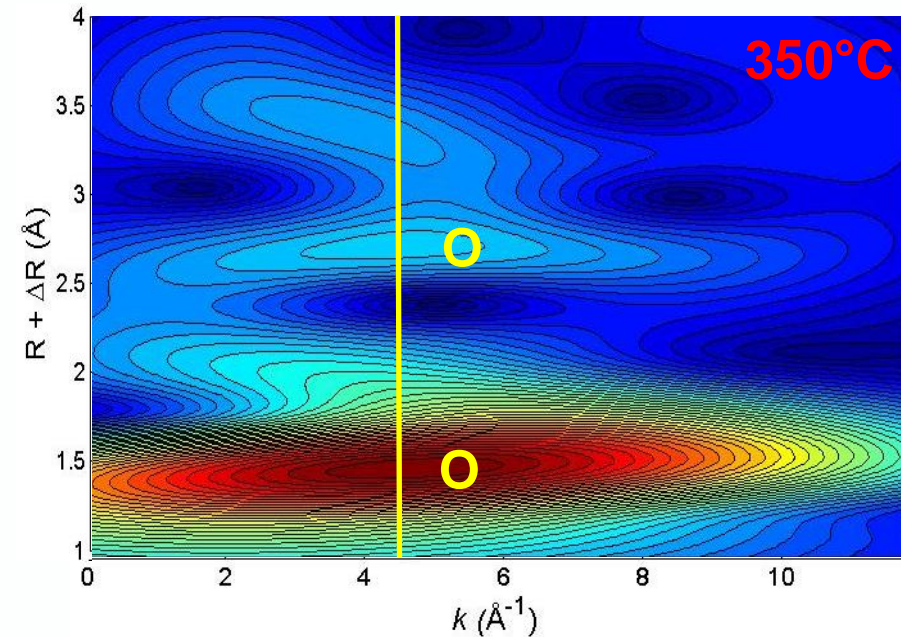
- Pt fcc metal structure + Pt-O shell: metal core + oxidized shell
→ sintering of dispersed PtO₂



350°C – 650°C – 250°C in O₂/He

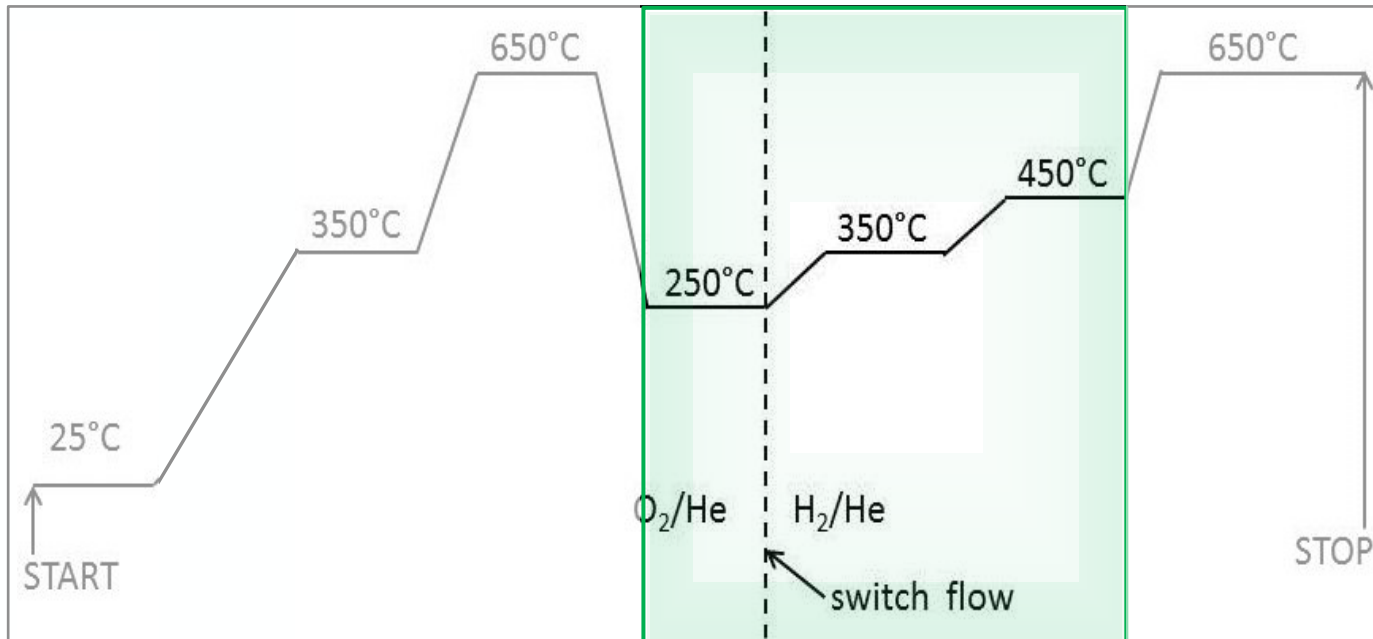
WT EXAFS

- O backscatterer (350°C) → oxidation 650°C → Pt backscatterer (250°C) after oxidation



350°C – 650°C – 250°C, O₂: sintering dispersed PtO₂ → Pt⁰ cluster core with oxidized outer shell

Results: Region 3



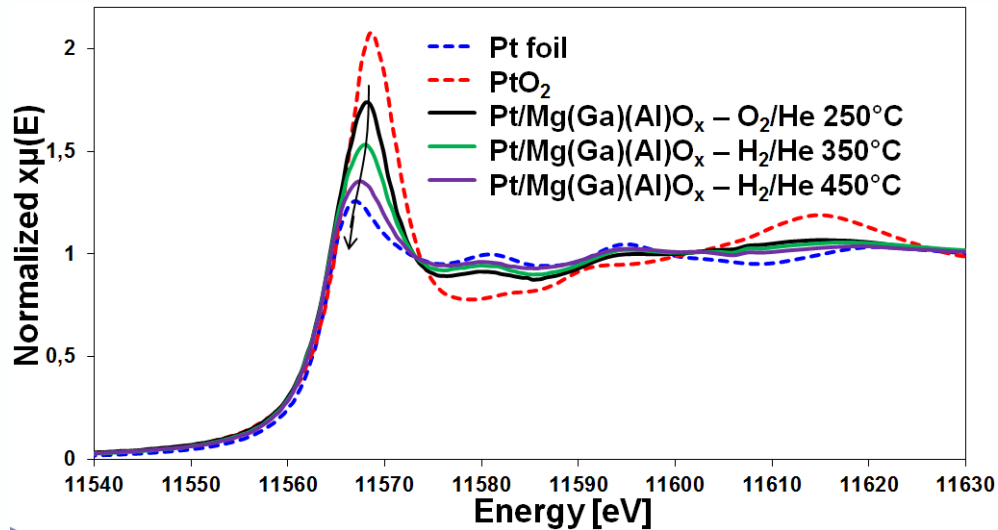
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250°C – 350°C – 450°C in H₂/He

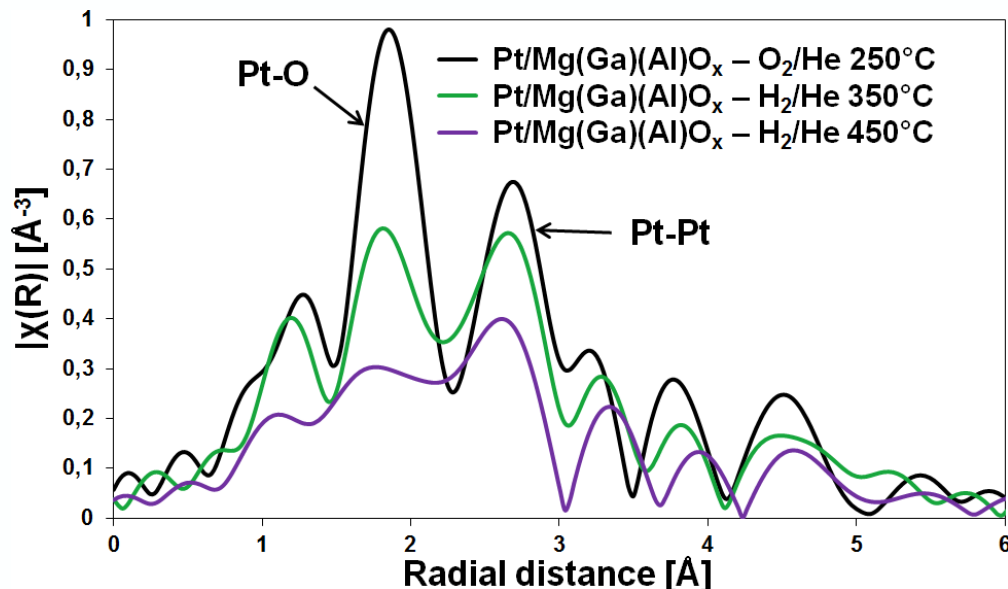


XANES

- WL decrease
- Evolution to Pt metal

FT EXAFS

- Cluster structure remains stable
- Pt-O/Pt-Pt decreases: reduction

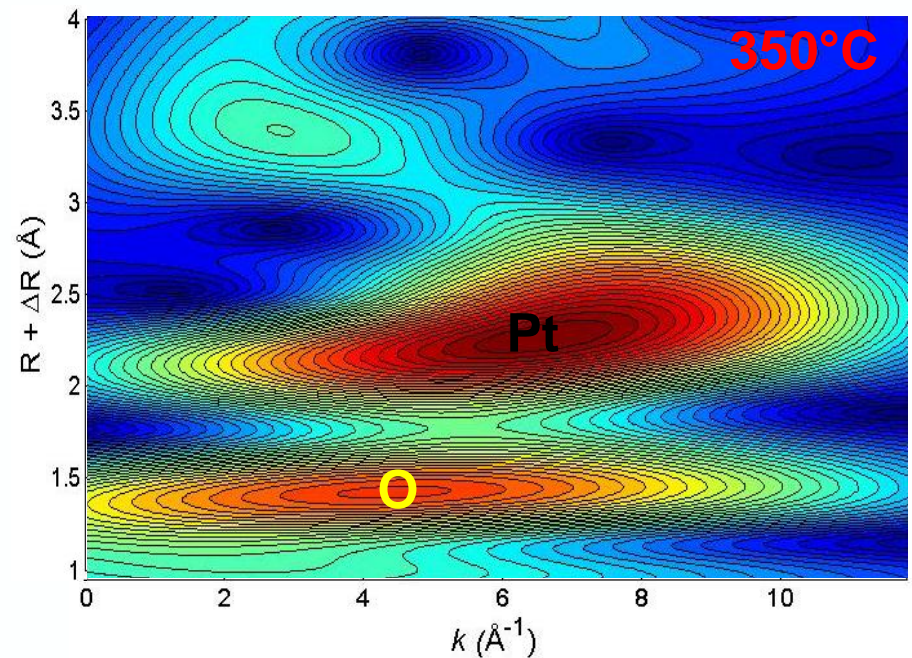
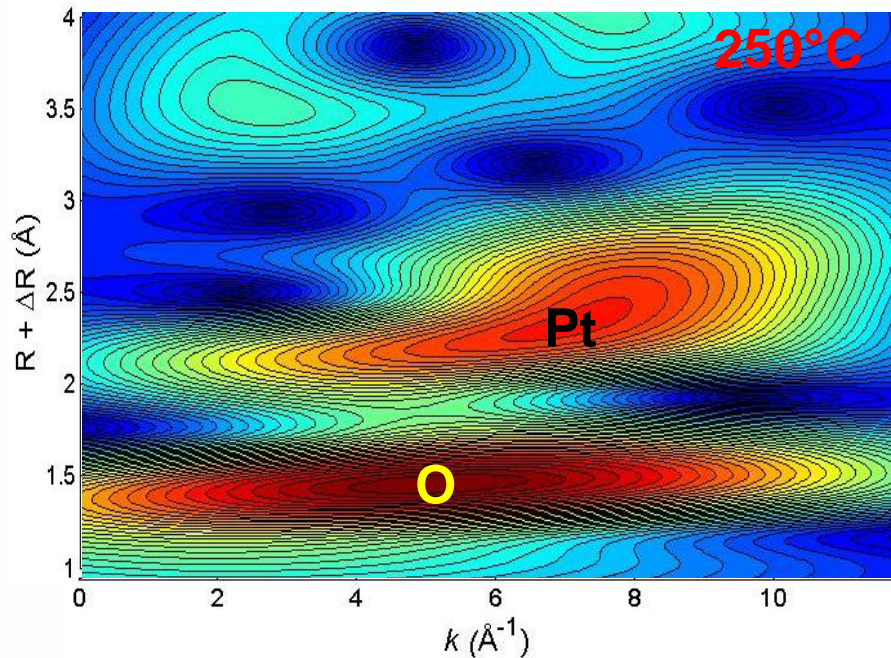


Condition	Pt-O/Pt-Pt amplitude
O ₂ /He 250°C	1,44
H ₂ /He 350°C	1,01
H ₂ /He 450°C	0,76

250°C – 350°C – 450°C in H₂/He

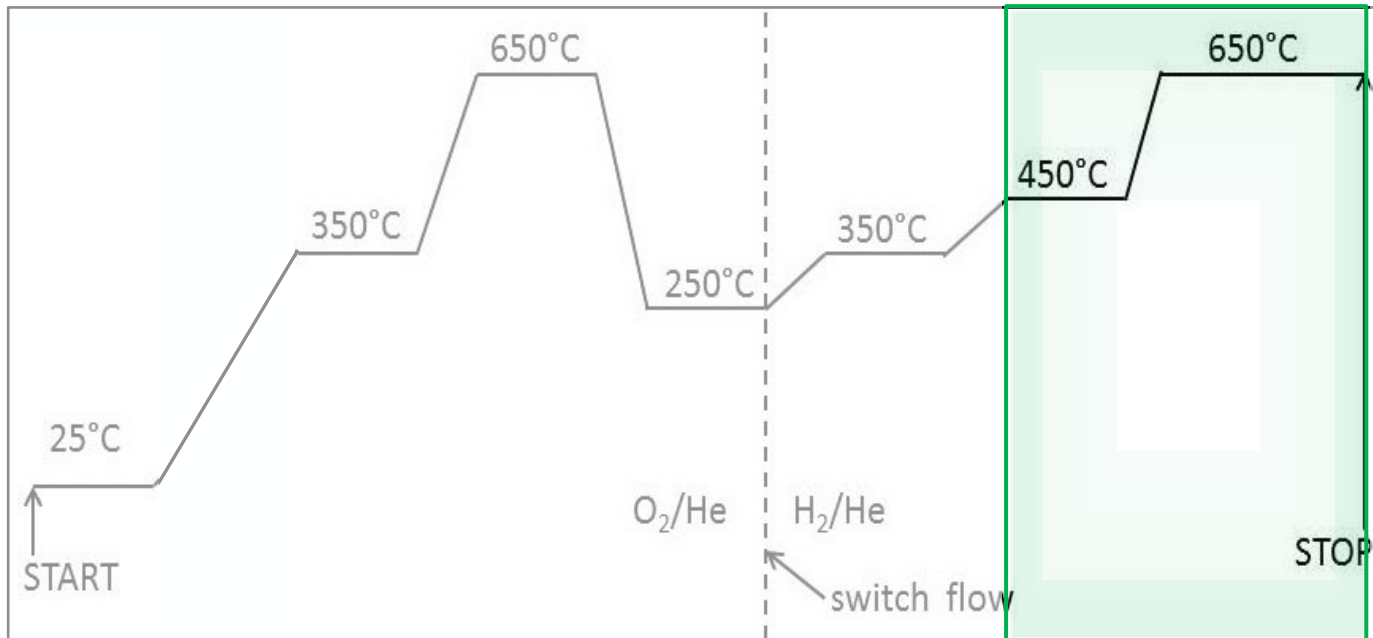
WT EXAFS

- Decreased O intensity relative to Pt intensity upon heating in H₂/He



250°C – 450°C, H₂: gradual reduction of Pt clusters

Results: Region 4



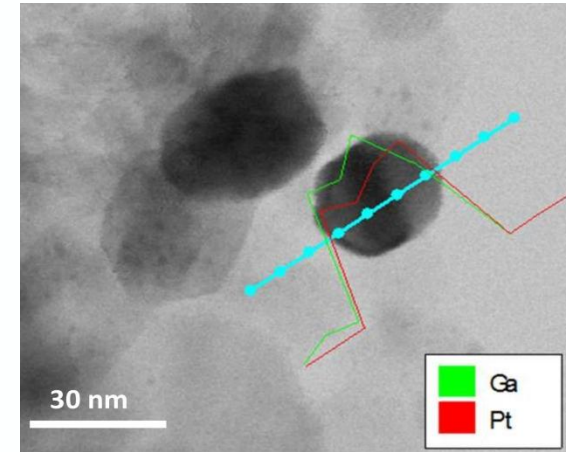
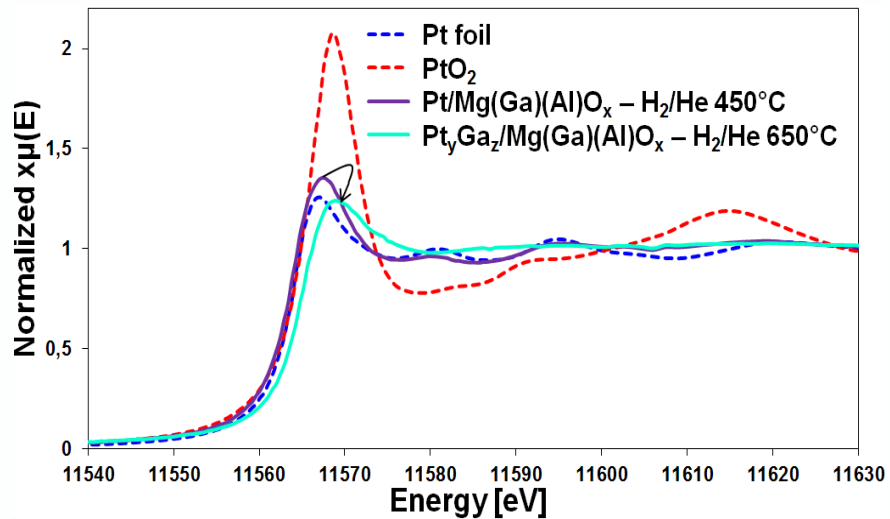
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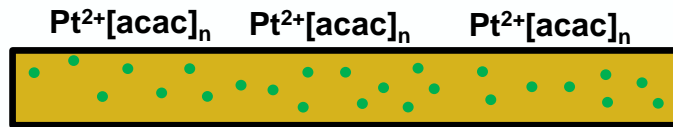
450 – 650°C in H₂/He



XANES

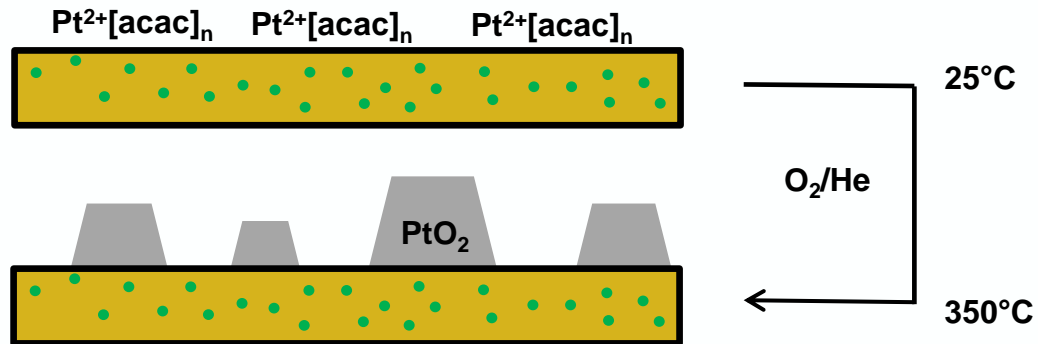
- Shift of edge energy to higher energy
- WL intensity decreases.
→ alloying ^[3] (confirmed by EDX)

Conclusions



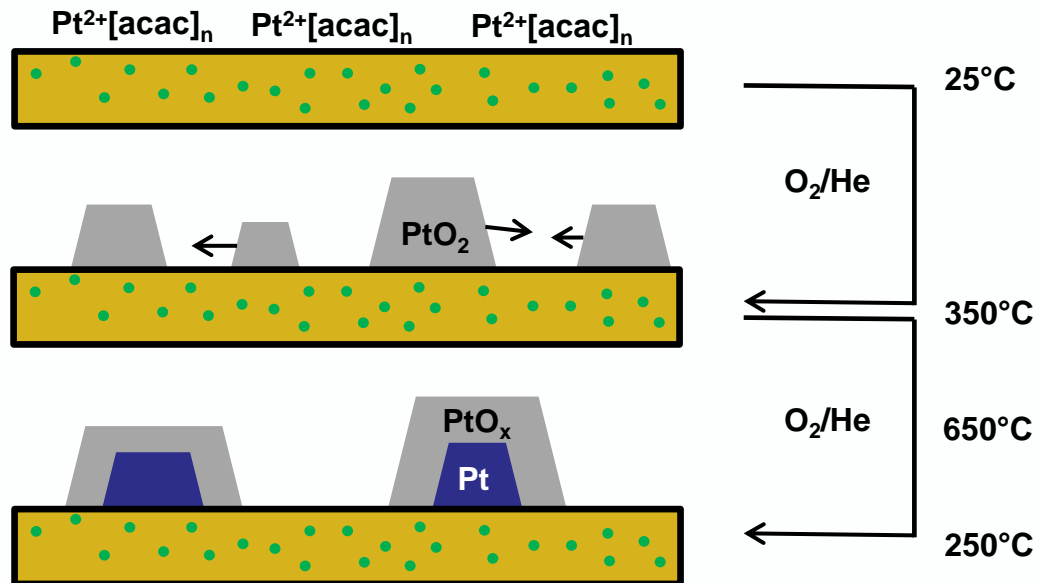
25°C

Conclusions



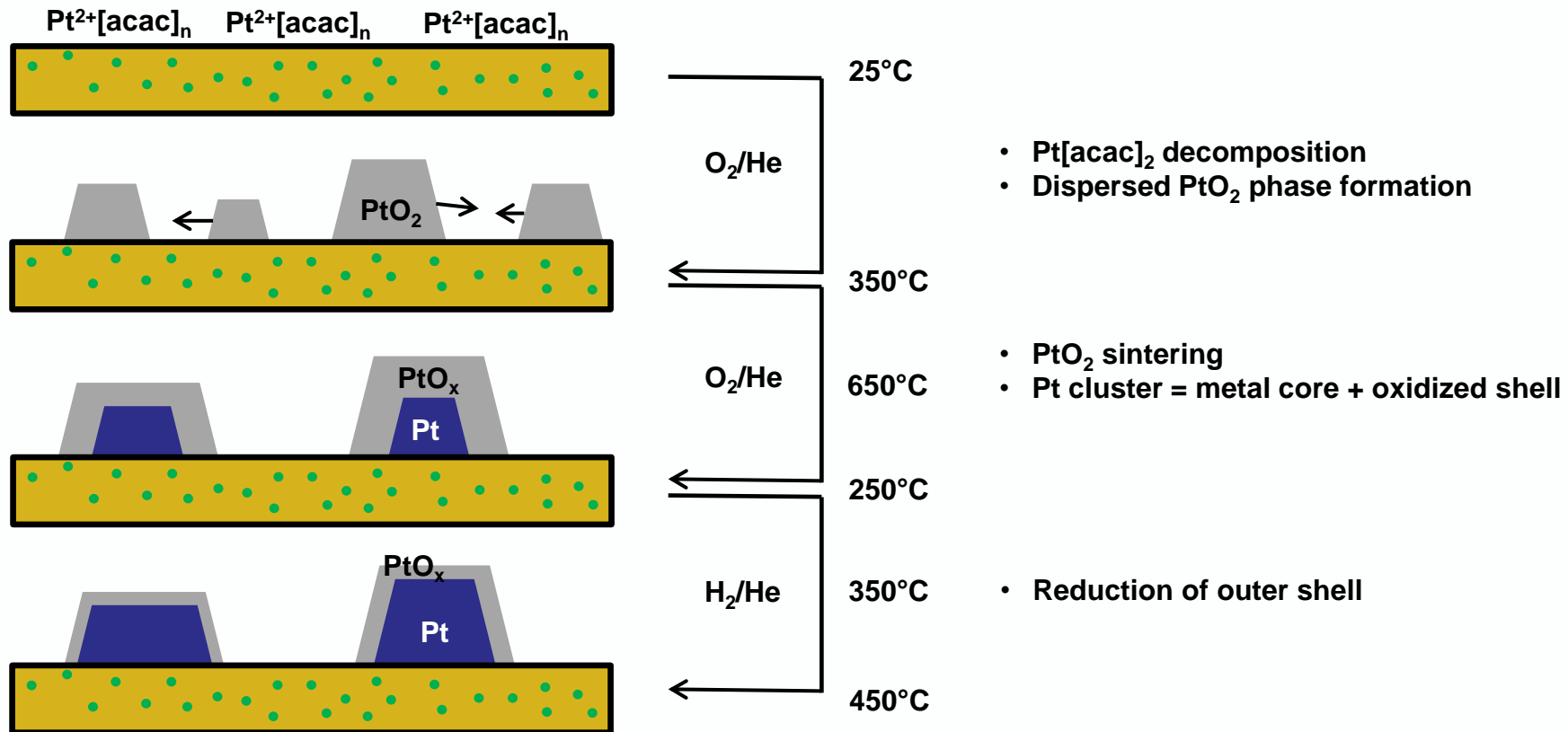
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- Dispersed PtO_2 phase formation

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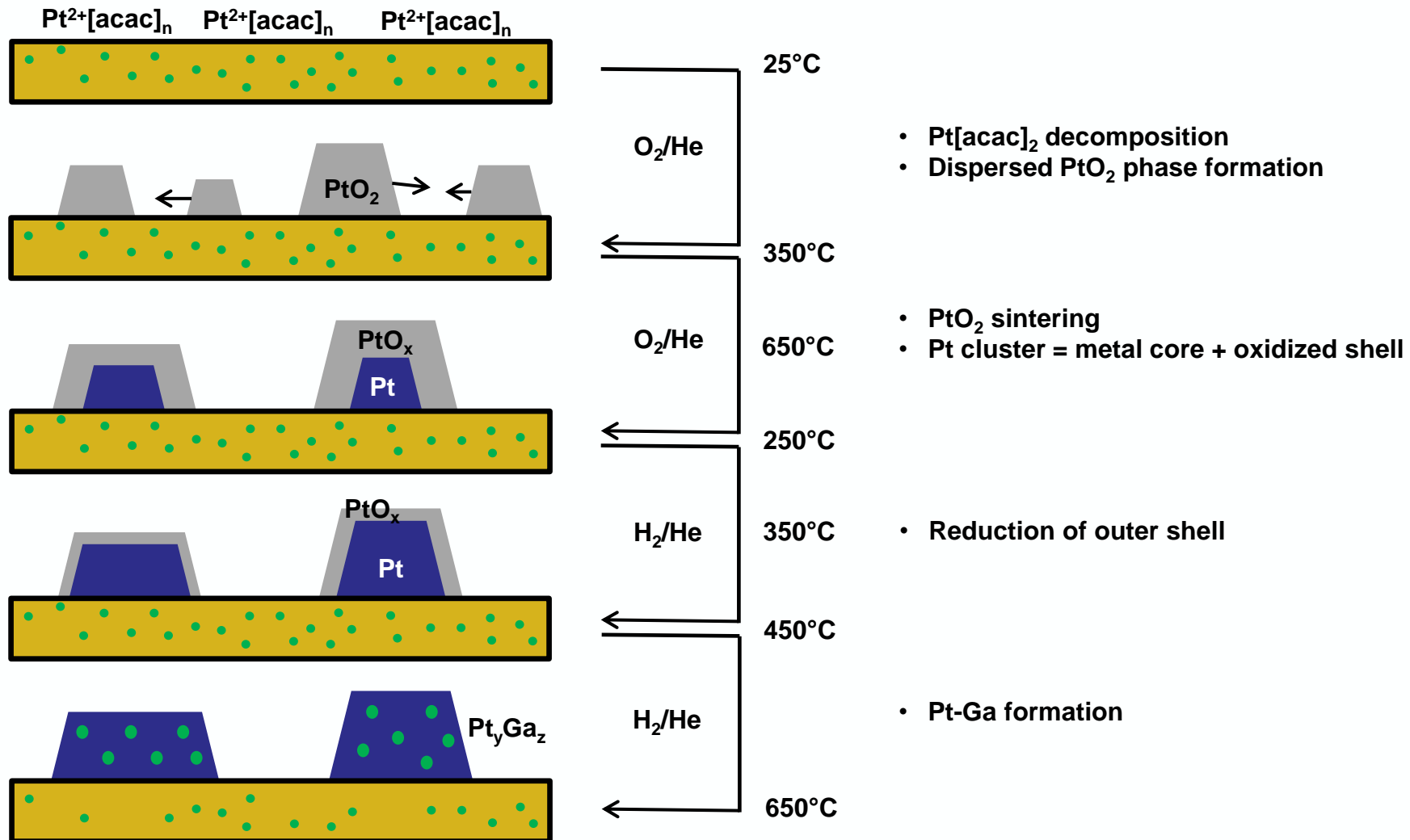


- $\text{Pt}[\text{acac}]_2$ decomposition
- Dispersed PtO_2 phase formation
- PtO_2 sintering
- Pt cluster = metal core + oxidized shell

Conclusions



Conclusions



Acknowledgements

The authors acknowledge

- support from S. Nikitenko and D. Banerjee (DUBBLE) at the ESRF synchrotron facility
- the Fund for Scientific Research Flanders (FWO)
- the 'Long Term Structural Methusalem Funding by the Flemish Government'
- Marie Curie IIF Fellowship of the European Commission.

Glossary

- XAS: X-ray Absorption Spectroscopy
- XANES: X-ray Absorption Near Edge Structure
- EXAFS: Extended X-ray Absorption Fine Structure
- FT: Fourier Transformation
- WT: Wavelet Transformation
- EDX: Energy Dispersive X-ray spectroscopy
- WL: White Line (first maximum at the absorption edge)
- fcc: face centered cubic structure
- absorber: atomic species absorbing X-ray fotons leading to the excitation their core-electrons.
- backscatterer: atomic species surrounding the absorber which scatter back the excited photo-electron to the absorber in the continuum.